SYNTEHSIS AND PROPERTIES OF TITANIA FILMS CONTAINING ANATASE, RUTILE AND HIGH-PRESSURE TiO₂-II

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The metastable TiO₂-II phase of titania has attracted interest as a material that, compared to more stable anatase and rutile phases, could have advantages in photocatalytic applications because of its narrower band gap as suggested on the basis of some theoretical and experimental studies [1,2]. However, the existing data are too contradictory yet. Differently from the results of Wang et al. [2], our recent experiments demonstrated that, as predicted in theoretical studies, the formation of TiO₂-II in thin films together with rutile caused only minor band gap narrowing (by around 0.06 eV) compared to that of anatase [3]. As the band gap of the mixed anatase and TiO2-II phases has been predicted to reach significantly smaller values [1], an additional study was performed to find possibilities to deposit this kind of films and characterize the optical properties of those. For this reason, TiO₂ was grown by atomic layer deposition from TiCl₄ and O₃ on α-Al₂O₃(0 0 0 1), α- $Al_2O_3(0\ 1\ -1\ 2)$ and SiO_2 substrates at growth temperatures (T_G) varied from 250 °C to 450 °C to obtain thin films with different phase compositions. X-ray diffraction and spectrophotometric measurements were carried out. The results obtained demonstrated that anatase phase grew on SiO₂ at $T_G = 250-400$ °C. On α -Al₂O₃(0 1 -1 2), a mixture of anatase and rutile were formed at 250 °C while at $T_G \ge 300$ °C, only rutile was obtained. In contrast, the films grown on α -Al₂O₃(0 0 0 1) at $T_G \ge 350$ °C contained high pressure TiO₂-II in addition to anatase and/or rutile. The relative amount of TiO2-II in the films increased with the decrease in the film thickness and with the increase of T_G to 450 °C. The studies performed for films grown at $T_G \ge 350$ °C on α -Al₂O₃(0 0 0 1) to different thicknesses revealed considerable band gap narrowing together with the formation of the TiO₂-II phase.

References

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